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SESSION 1: MEMS and Sensors

2016 March 29, 9:00 – 10: 20

Co-Chairs: Stewart Smith, *The University of Edinburgh, UK*

SESSION 2: Thermal Issues

2016 Mar 29, 11:00 – 12:20

Co-Chairs: Anthony J. Walton, *University of Edinburgh, UK*
Hi-Deok Lee, *Chungnam National University, Korea*

SESSION 3: Arrayed Test Structures

2016 Mar 29, 14:10 – 15:40

Co-Chairs: Tatsuya Ohguro, *Toshiba, Japan*
Christopher Hess, *PDF Solutions, USA*

SESSION 4: Parameter Extraction

2016 Mar 29 16:10 – 17:10

Co-Chairs: Kjell Jeppson, *Chalmers University, Sweden*

SESSION 5: RF and Power Devices

2016 Mar 30 9:20 – 10:20

Co-Chairs: Colin McAndrew, *NXP Semiconductors, USA*

SESSION 6: Capacitances

2016 Mar 30 10:50 – 11:50

Co-Chairs: Hans P. Tuinhout, *NXP Semiconductor, The Netherlands*
Chadwin Young, *University of Texas at Dallas, USA*

SESSION 7: Memories

2016 Mar 30 13:40 – 14:40

Co-Chairs: Yuzo Fukuzaki, *Sony Corporation, Japan*
Carlo Cagli, *CEA/LETI, France*

SESSION 8: Non-Volatile Memories

2016 Mar 30 15:30 – 17:00

Co-Chairs: Jurriaan Schmitz*, University of Twente, The Netherlands*
Satoshi Habu, *Keysight Technologies, Japan*

SESSION 9: Process and Device Characterization

2016 Mar 31 9:00 – 10:20

Co-Chairs: Larg Weiland, *PDF Solutions, USA*
Bing-Yue Tsui, *National Chiao Tung University, Taiwan*

SESSION 10: Materials Characterization

2016 Mar 31 10:50 – 12:10

Co-Chairs: Bill Verzi, *Agilent Technologies, USA*